

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/574,121 SHIRAISHI ET AL.	
		Examiner	Art Unit Dwight Alex C. Tejano 4112	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0140978	10-2002	Urabe et al.	358/1.16
*	B	US-2003/0120745	06-2003	Katagishi et al.	709/217
*	C	US-2003/0036425	02-2003	Kaminkow et al.	463/25
*	D	US-7,305,233	12-2007	Paul et al.	455/418
*	E	US-7,117,519	10-2006	Anderson et al.	725/105
*	F	US-2005/0278422	12-2005	Prust, Mitch	709/203
*	G	US-2005/0206749	09-2005	Miyazaki, Hiroyuki	348/231.99
*	H	US-2004/0003411	01-2004	Nakai et al.	725/105
*	I	US-6,715,003	03-2004	Safai, Mohammad A.	710/33
J	US-				
K	US-				
L	US-				
M	US-				

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.